

Making the Right Hand Turn to Power Efficient Computing

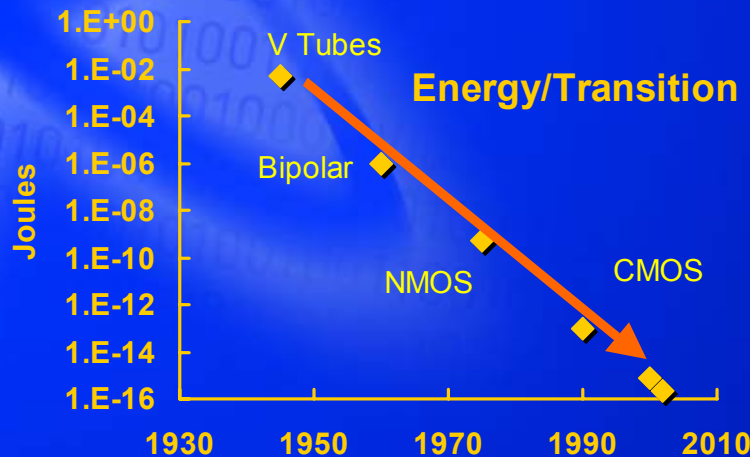
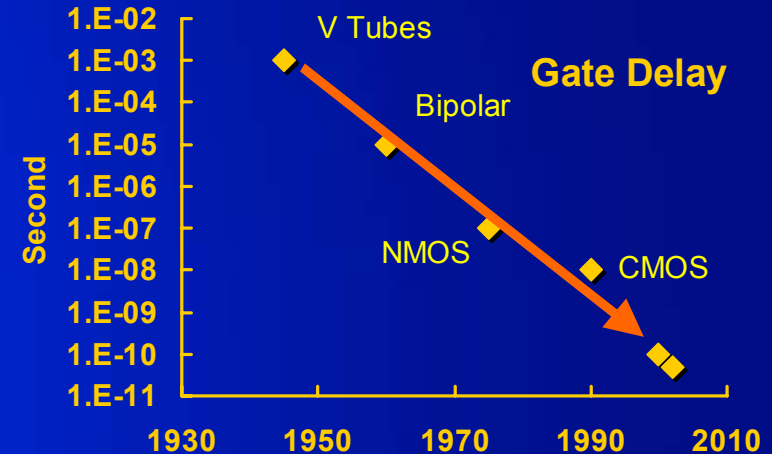
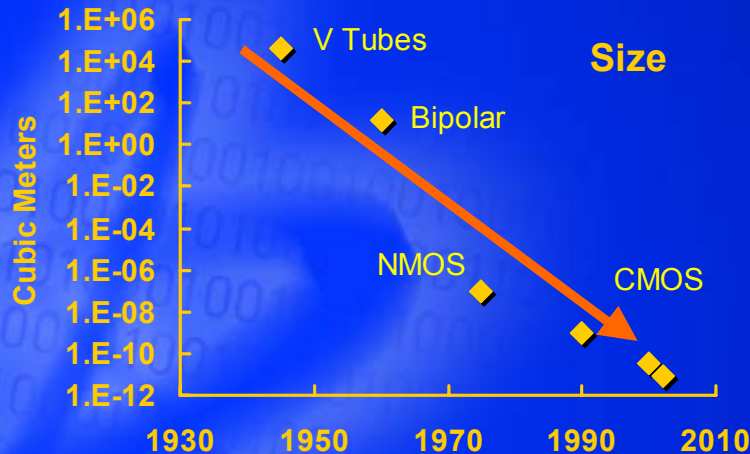
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Outline

- Technology scaling
- Types of efficiency
- Making the right hand turn

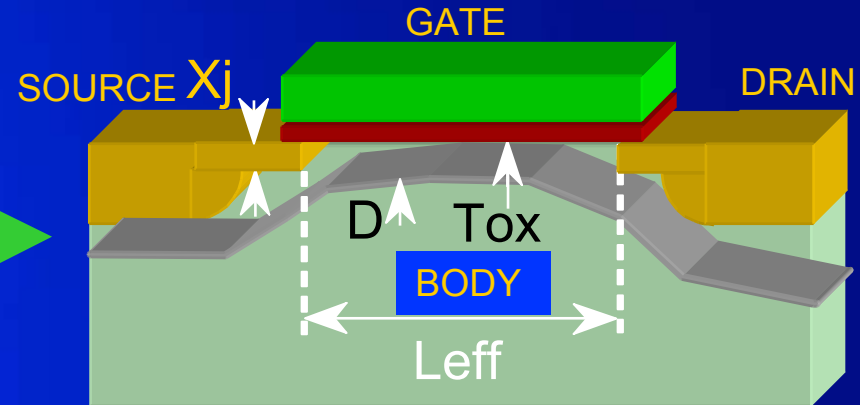
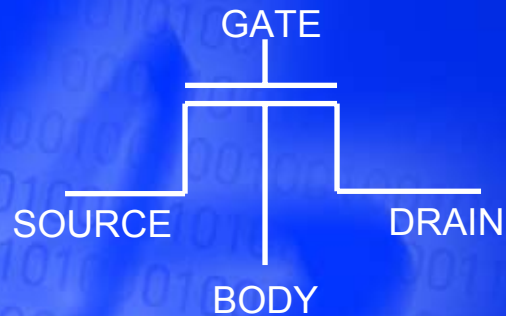
Historic Perspective



| | | |
|---------|---|---------|
| V Tubes | ⇒ | Bipolar |
| Bipolar | ⇒ | NMOS |
| NMOS | ⇒ | CMOS |
| CMOS | ⇒ | ? |

Scaling will continue

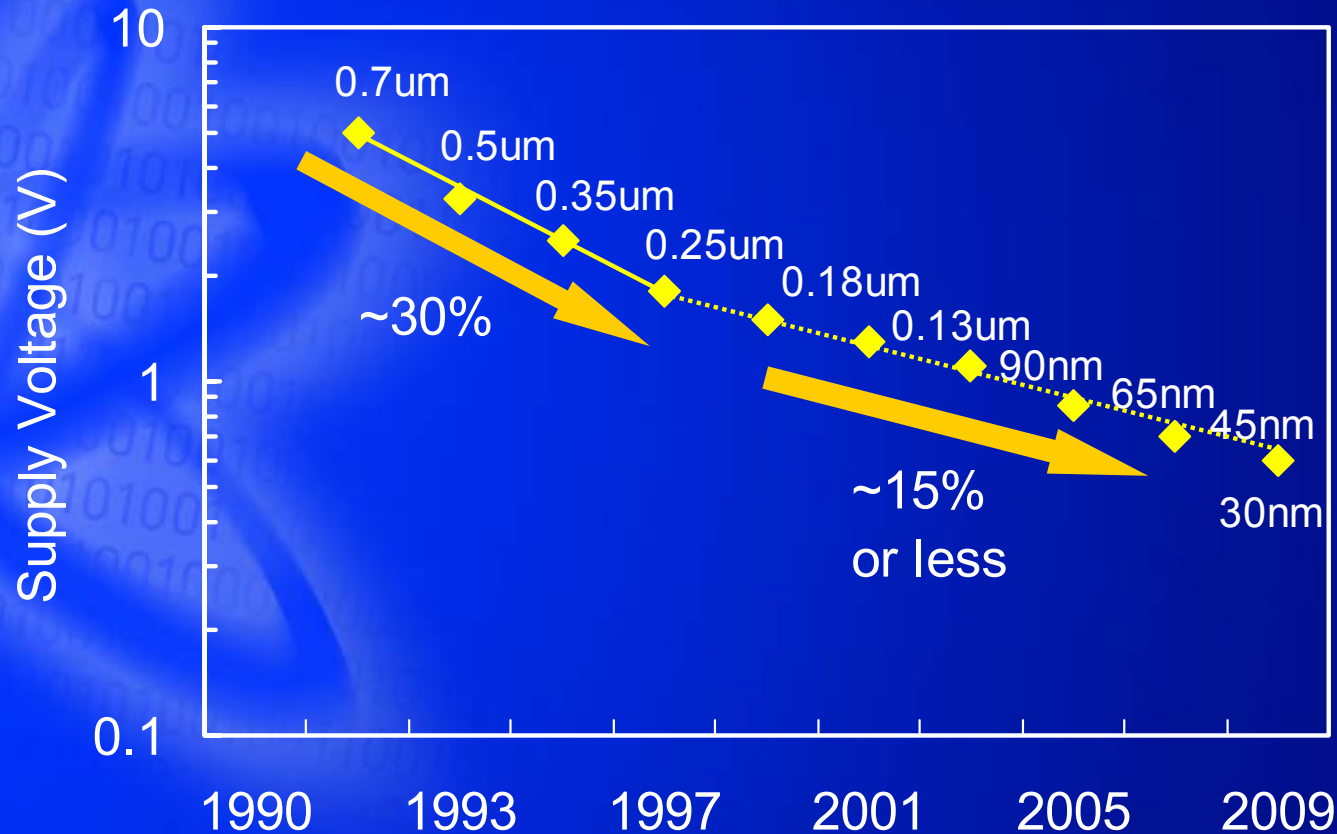
Technology Scaling



| | |
|------------------------------------|---------------------------------------|
| X & Y Dimensions scale down by 30% | Doubles transistor density |
| Z-Oxide thickness scales down | Faster transistor, higher performance |
| Vcc & Vt scaling | Lower active power |

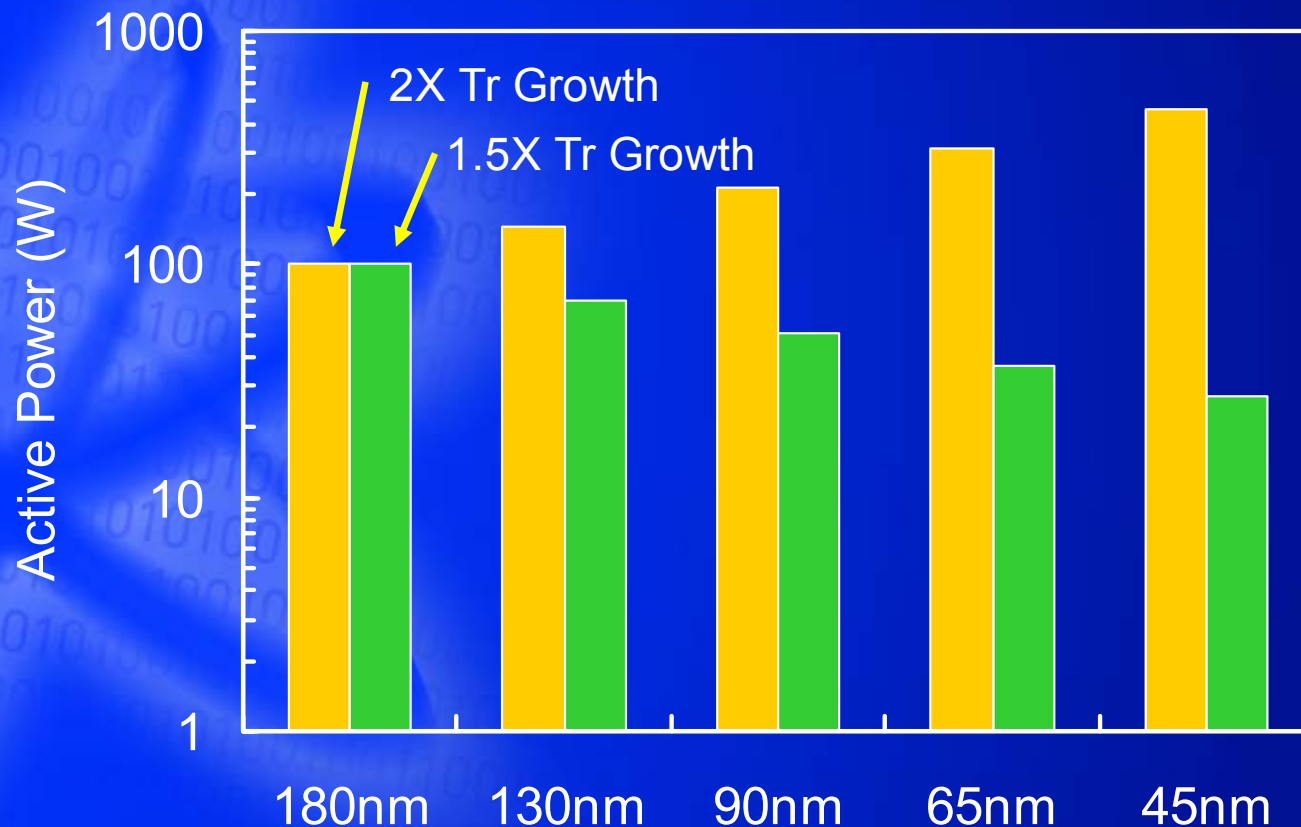
Technology scaling is a great thing

Supply Voltage Scaling



Supply voltage scaling has slowed

Active Power Projection

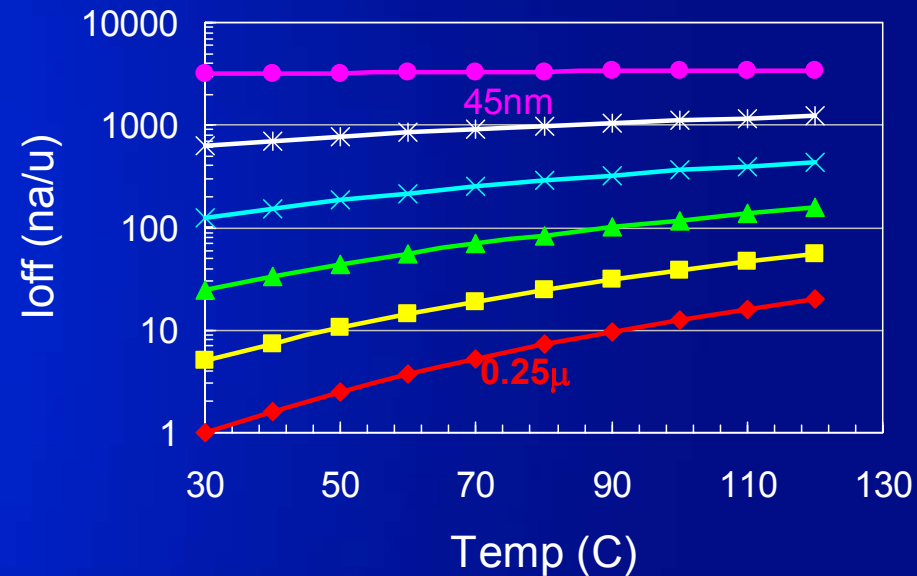
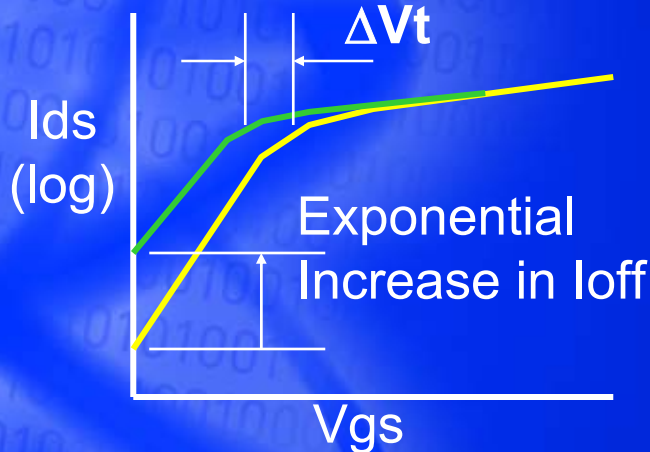


Assumptions:
- 15% Vdd scaling
- 50% Freq scaling
(Per generation)

Power will limit transistor integration

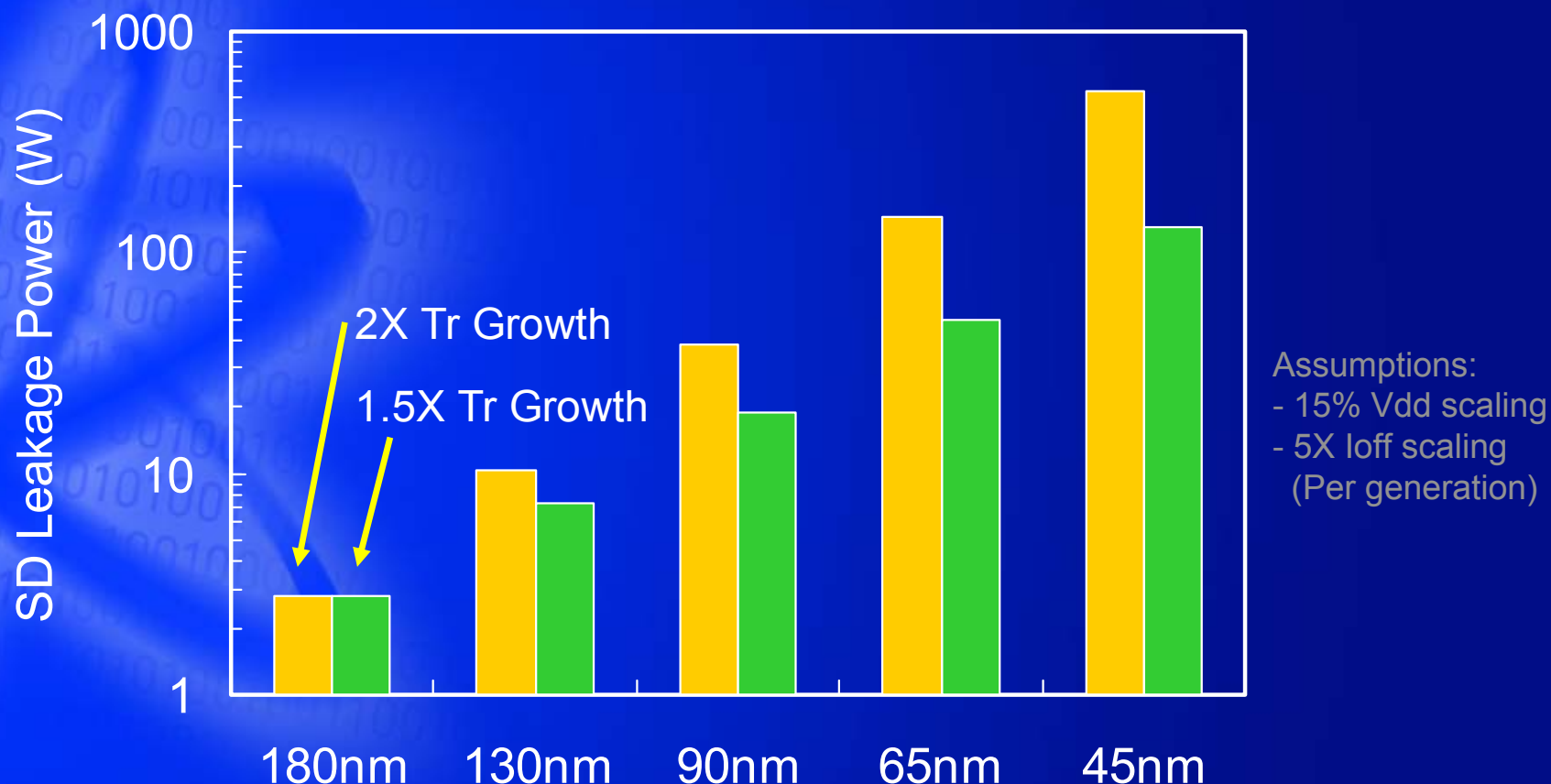
Sub-threshold Leakage

MOS Transistor Characteristics



Transistors will be *dimmers*, not *switches*

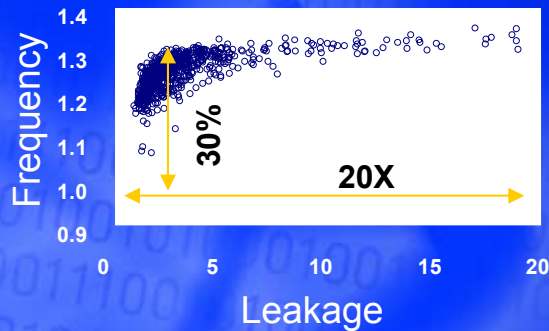
SD Leakage Power



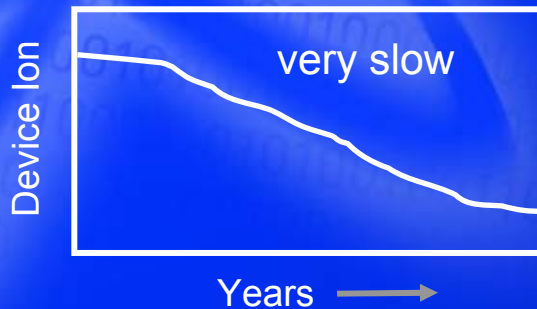
Excessive sub-threshold leakage power

Variations in P, V, and T

Process

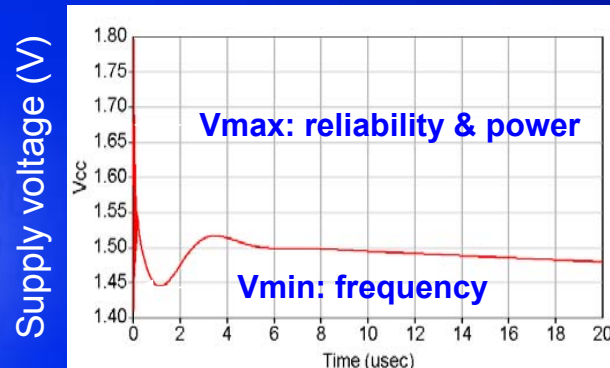


- Die-to-die variation
- Within-die variation
- Static for each die



Time dependent degradation

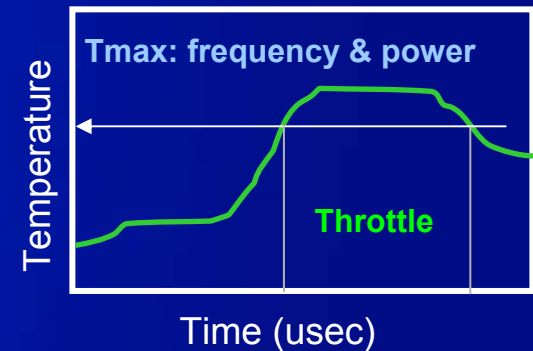
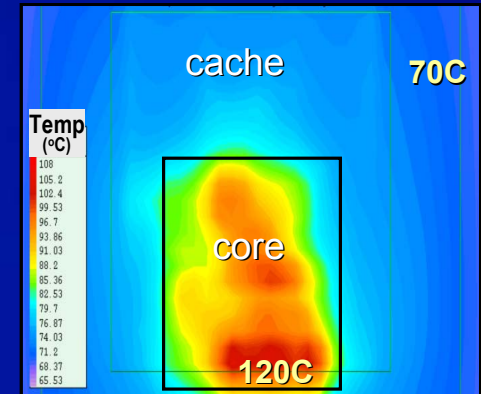
Voltage



Time (usec)

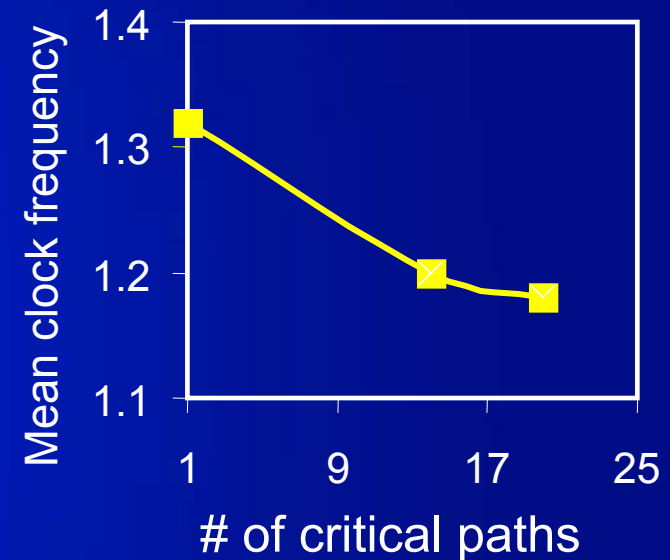
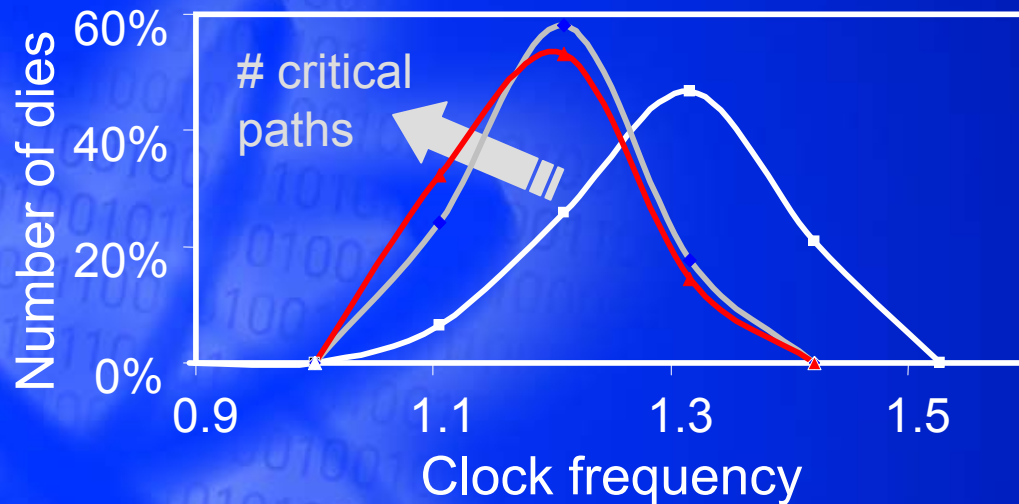
- Chip activity change
- Current delivery RLC
- Dynamic: ns to 10-100us
- Within-die variation

Temperature



- Activity & ambient change
- Dynamic: 100-1000us
- Within-die variation

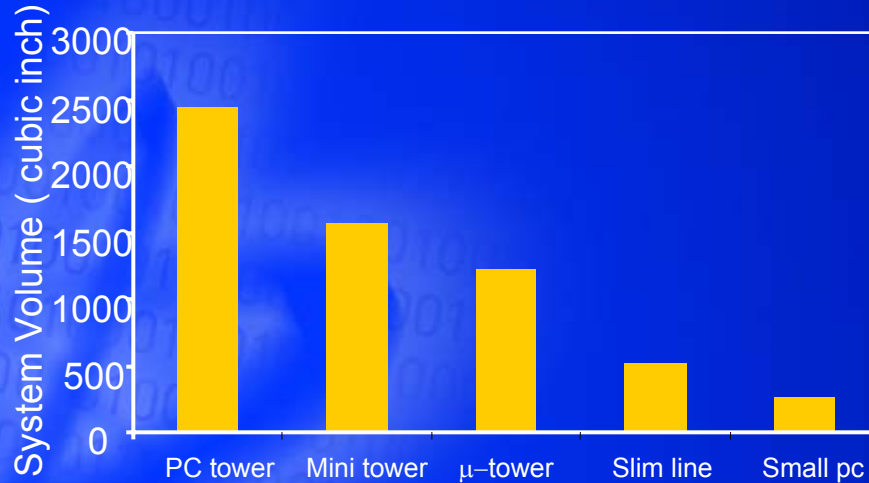
Impact of Critical Paths



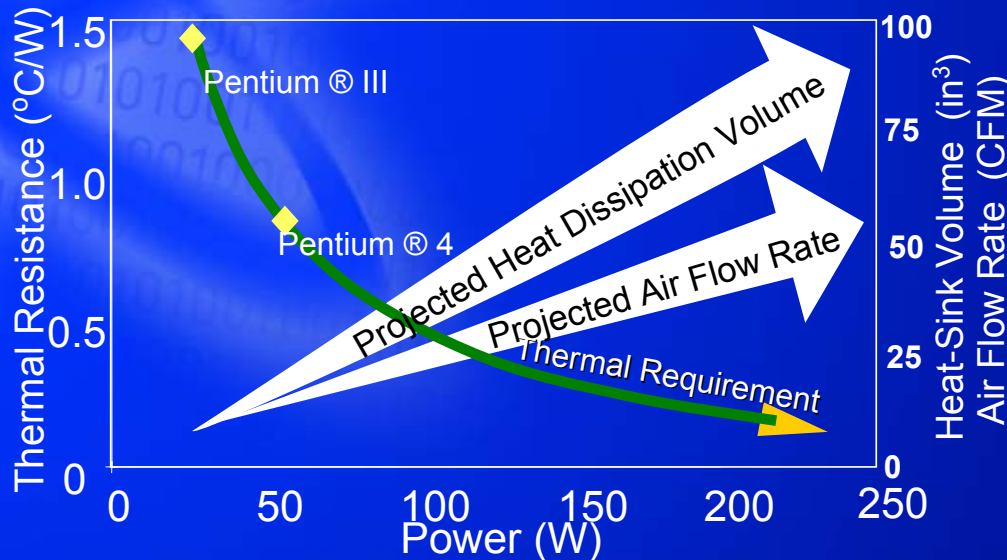
Impact of transistor parameter variations:

- Wide distribution of circuit frequency
- Lower mean freq with # of critical paths
- Encourages more localized, clustered designs

Tough Platform Demands

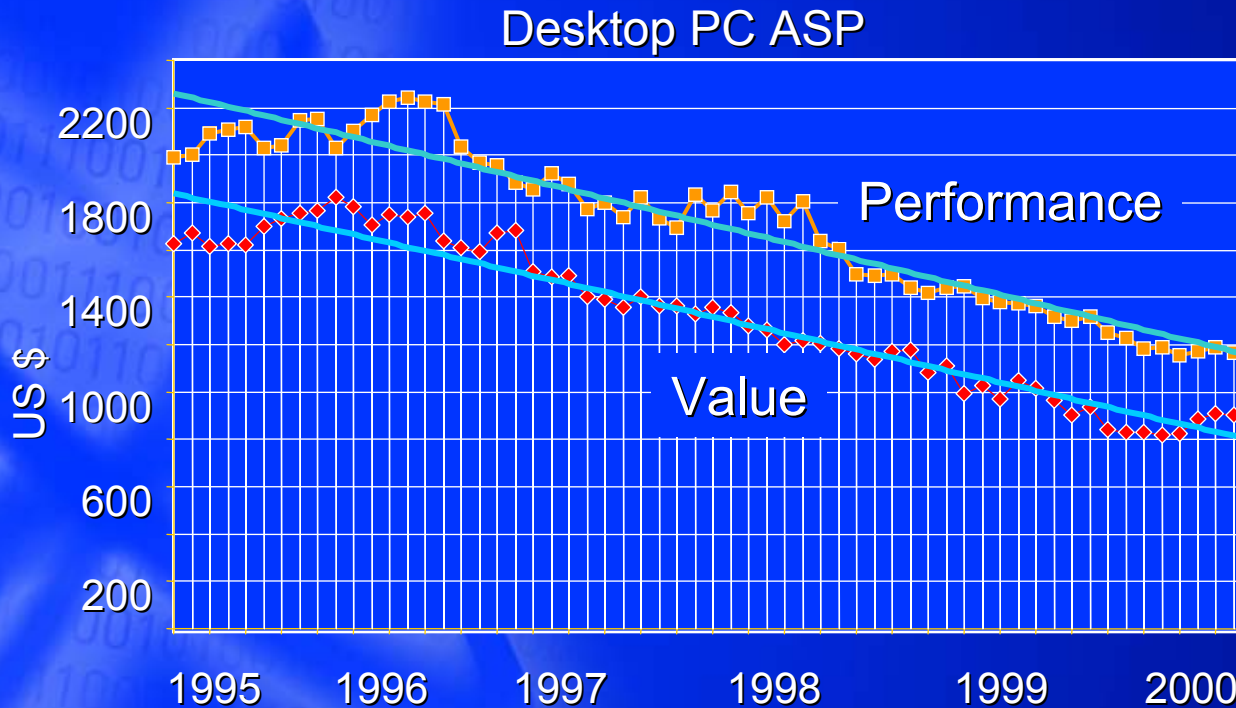


Shrinking volume
Reduced Noise
Yet, Higher Performance



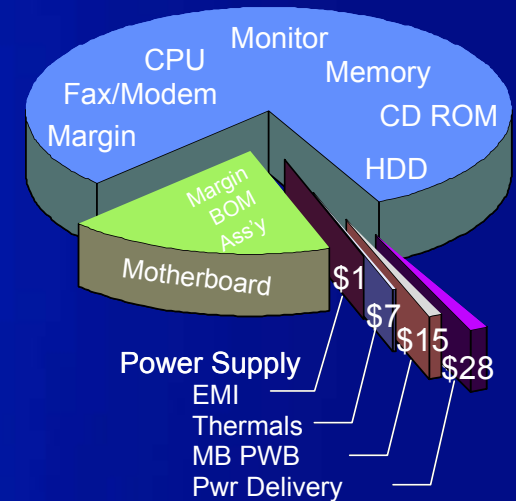
Reduced thermal budget
Higher heat sink volume
Higher air flow rate

BOM Cost Squeeze



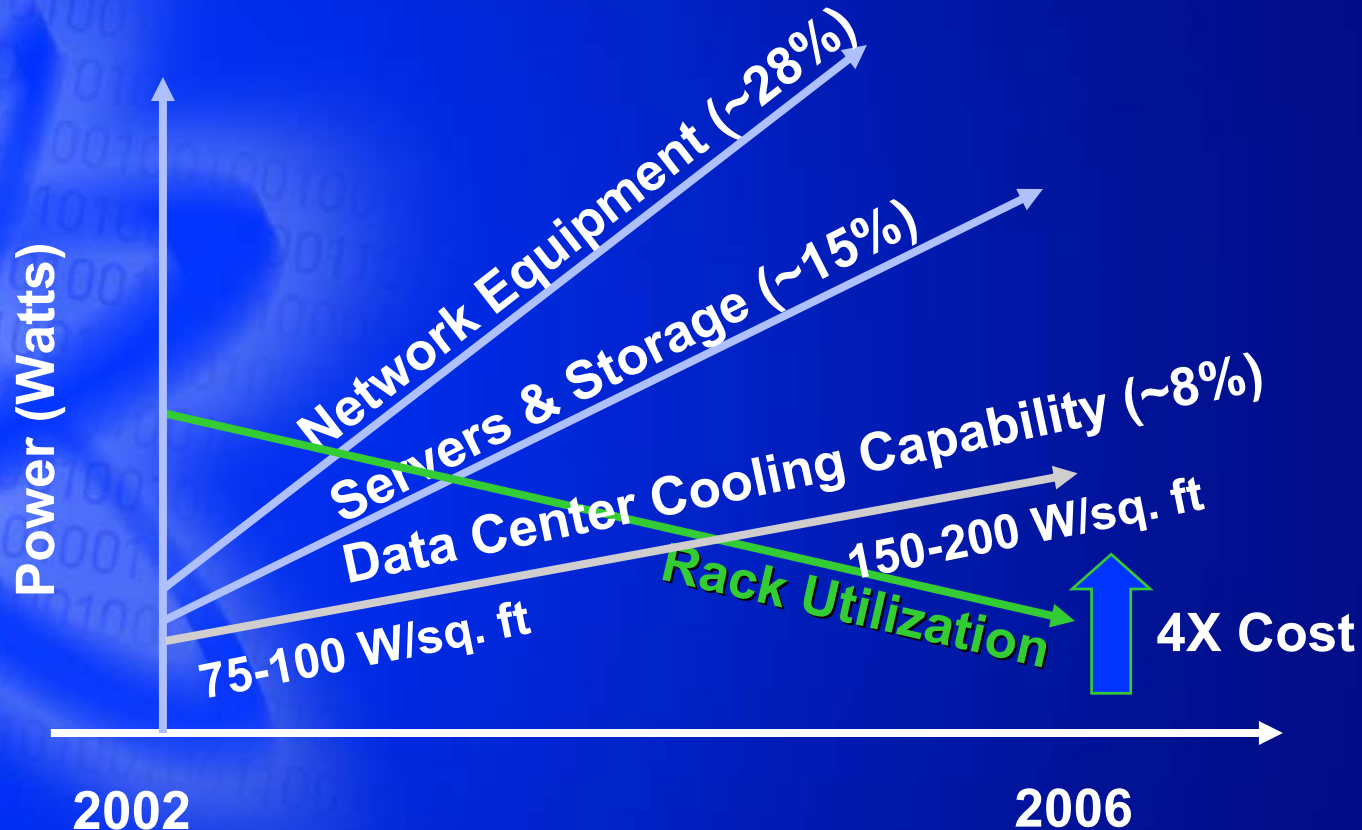
Source: Dataquest Personal Computers

\$2000 PC cost ('97)



Budget for power and cooling is shrinking

Data Centers: Rack Mount Limits

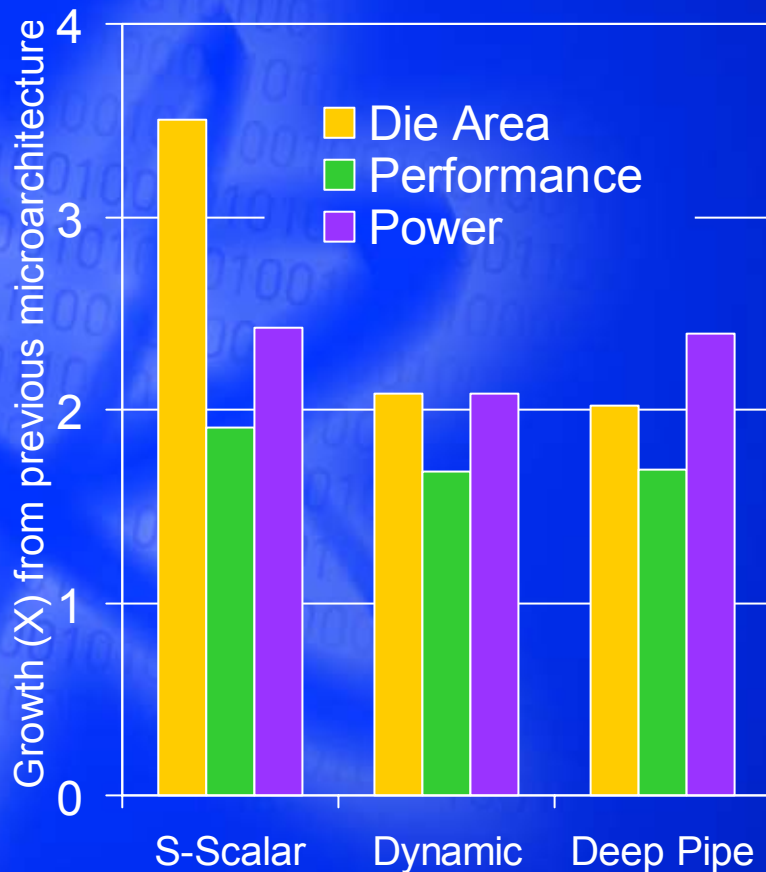


Wasted space and higher cost in future

Outline

- Technology scaling
- Looking at efficiency
- Making a right hand turn

Power Efficiency



In the same process technology, compare:

Scalar \Rightarrow Super-scalar

\Rightarrow Dynamic

\Rightarrow Deep pipe

2-3X Growth in area

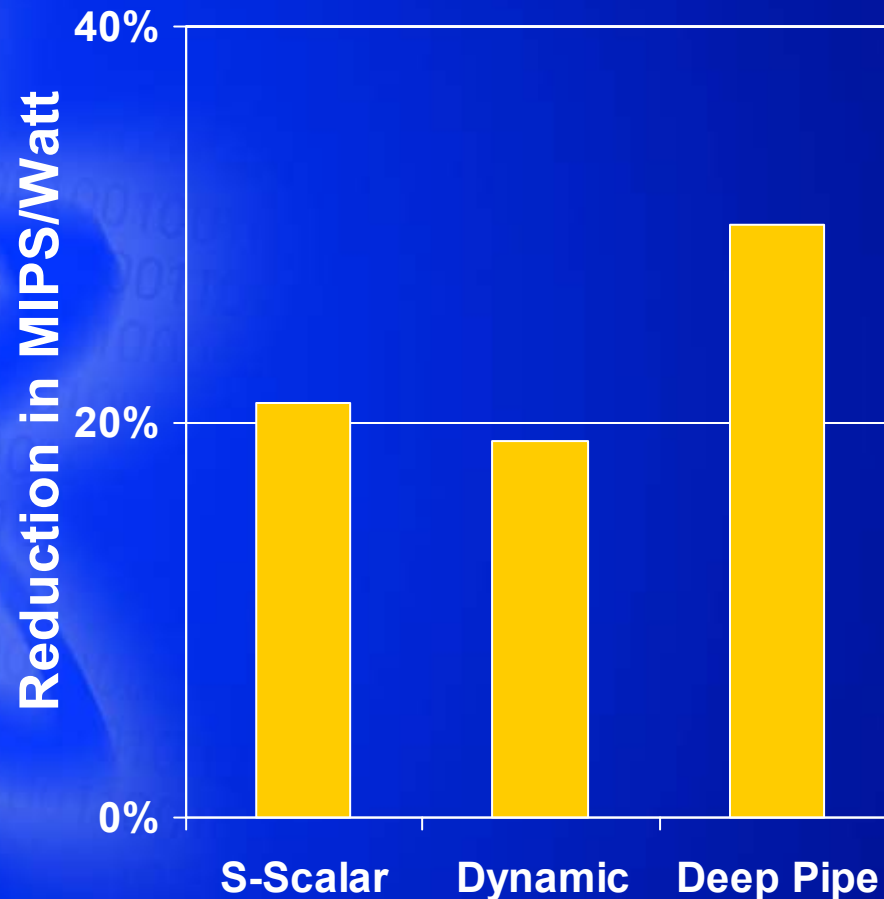
~1.4X Growth in Integer Performance

~1.7X Growth in Total Performance

2-2.5X Growth in Power

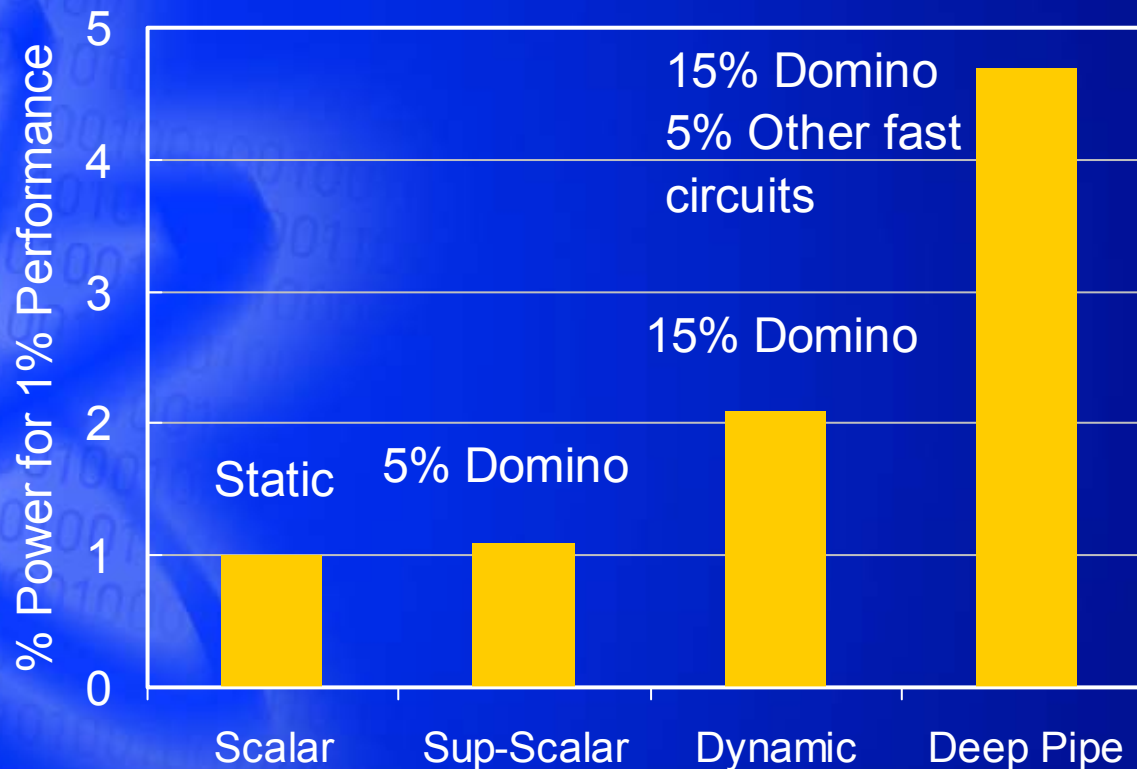
2-2.5x growth in power / generation

Energy Efficiency



20-30% drop in energy efficiency / generation

Circuit Efficiency



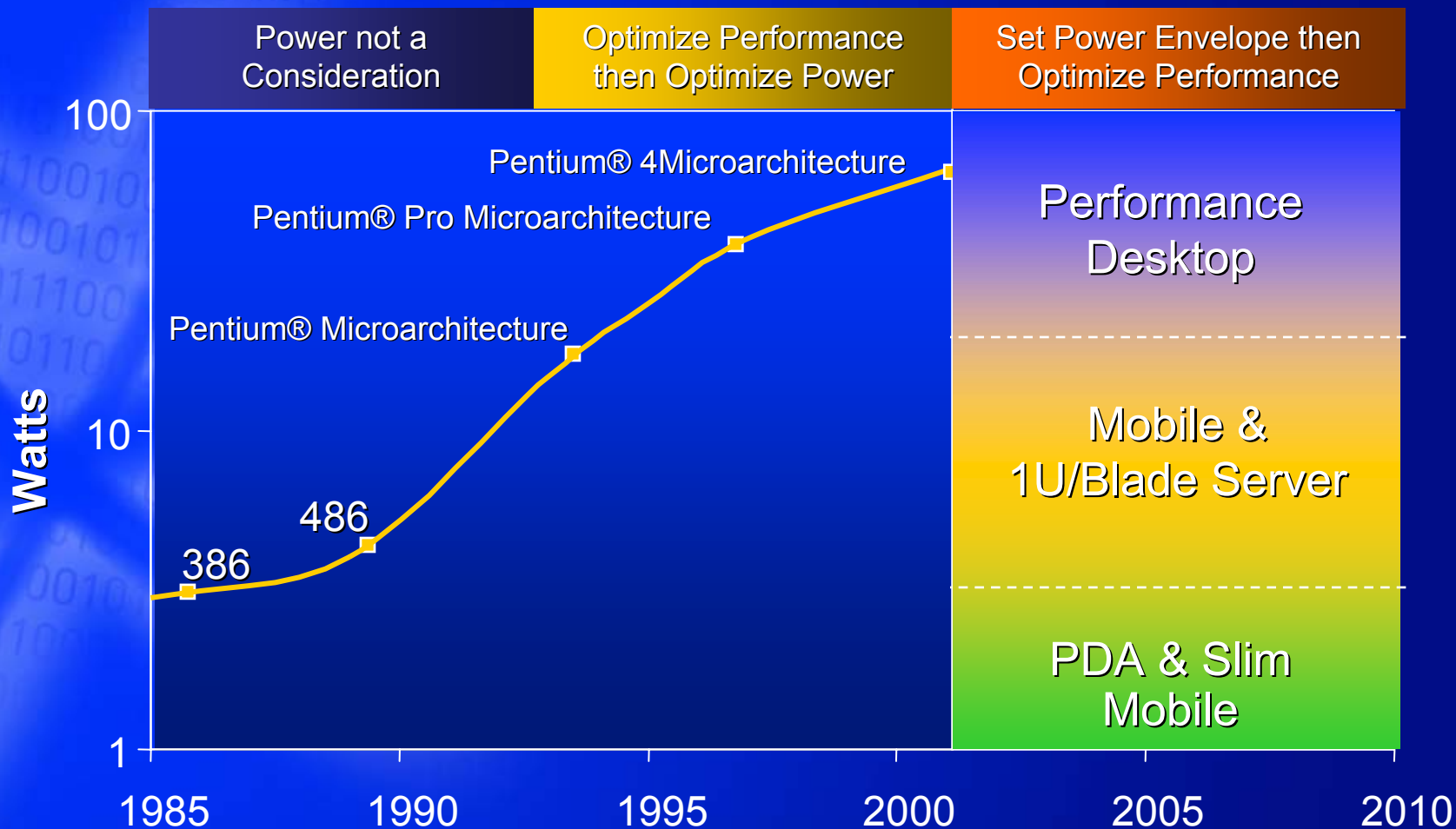
Assumptions:
Activity: Static = 0.2,
Domino = 0.5
Clock consumes 40%
of full chip power

Faster circuits contribute to power inefficiency

Outline

- Technology scaling
- Types of efficiency
- Making a right hand turn

Power Comes First



Business as usual is not an option

Low Power and High Performance

- **Maximize battery life (fixed energy)**

$$\text{Energy} = \text{Texec} * \text{Power} \approx (1/\text{Perf}) * \text{Power}$$

Increasing the Performance by 10% and the Power by 10% will end up with same battery life

- **Maximize performance within a given power envelope (Thermal constrains)**

$$f \approx K * V$$

$$\text{Power} = \alpha * C * V^2 * f \approx \alpha * C * f^3$$

$$\Delta \text{power} / \text{Power} = ((f + \Delta f)^3 - f^3) / f^3 \approx 3 \Delta f / f$$

$$\text{Perf} = \text{IPC} * f$$

➔ *The right trade off between Performance and Power*

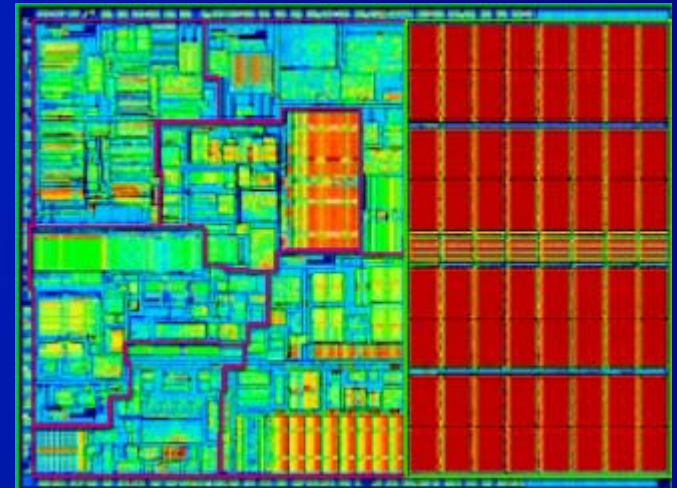
$\Delta \text{IPC} < 3 \Delta \text{Power}$ is the metric

“Less is More”

- Strive to accomplish the same task in less energy and less time
 - Higher performance at lower energy can always be traded with same performance at lower power
- Methodology works at all levels
 - Aggressive clock gating
 - Caching - dumb and smart
 - Better branch predictors
 - Smart work reduction
 - Prioritize useful over speculated work
 - Fixed functions

“Less is More” in Baniyas

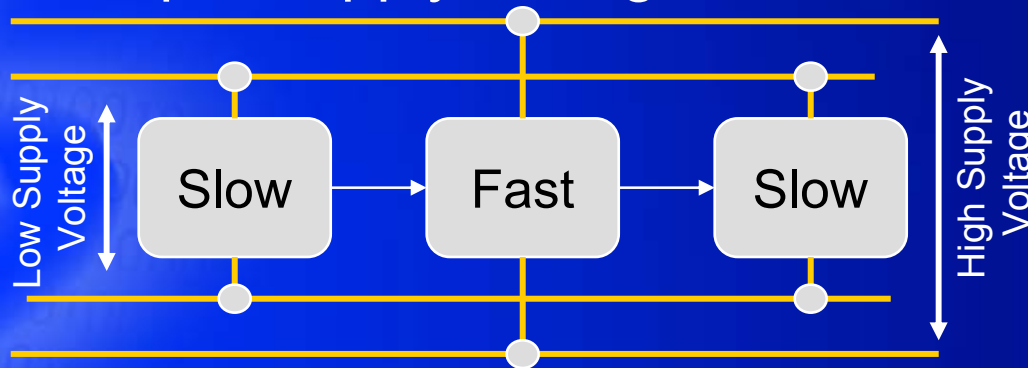
- Improved branch prediction
 - Over 20% fewer branch mispredictions
- Dedicated stack manager
 - Over 5% uop reduction
- Uop fusion
 - Over 10% uop reduction
- Big L2 cache



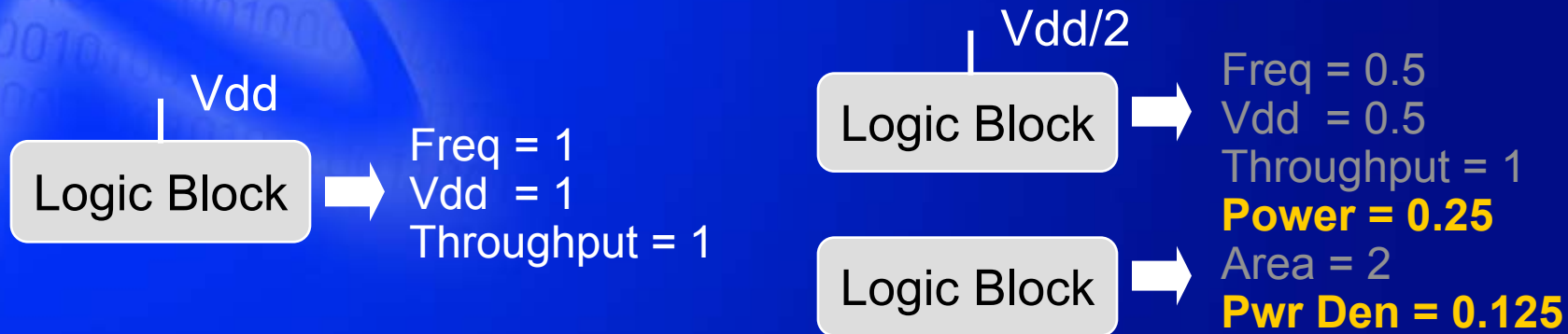
Achieving Higher Performance at Lower Power

Reducing Active Power

Multiple Supply Voltages

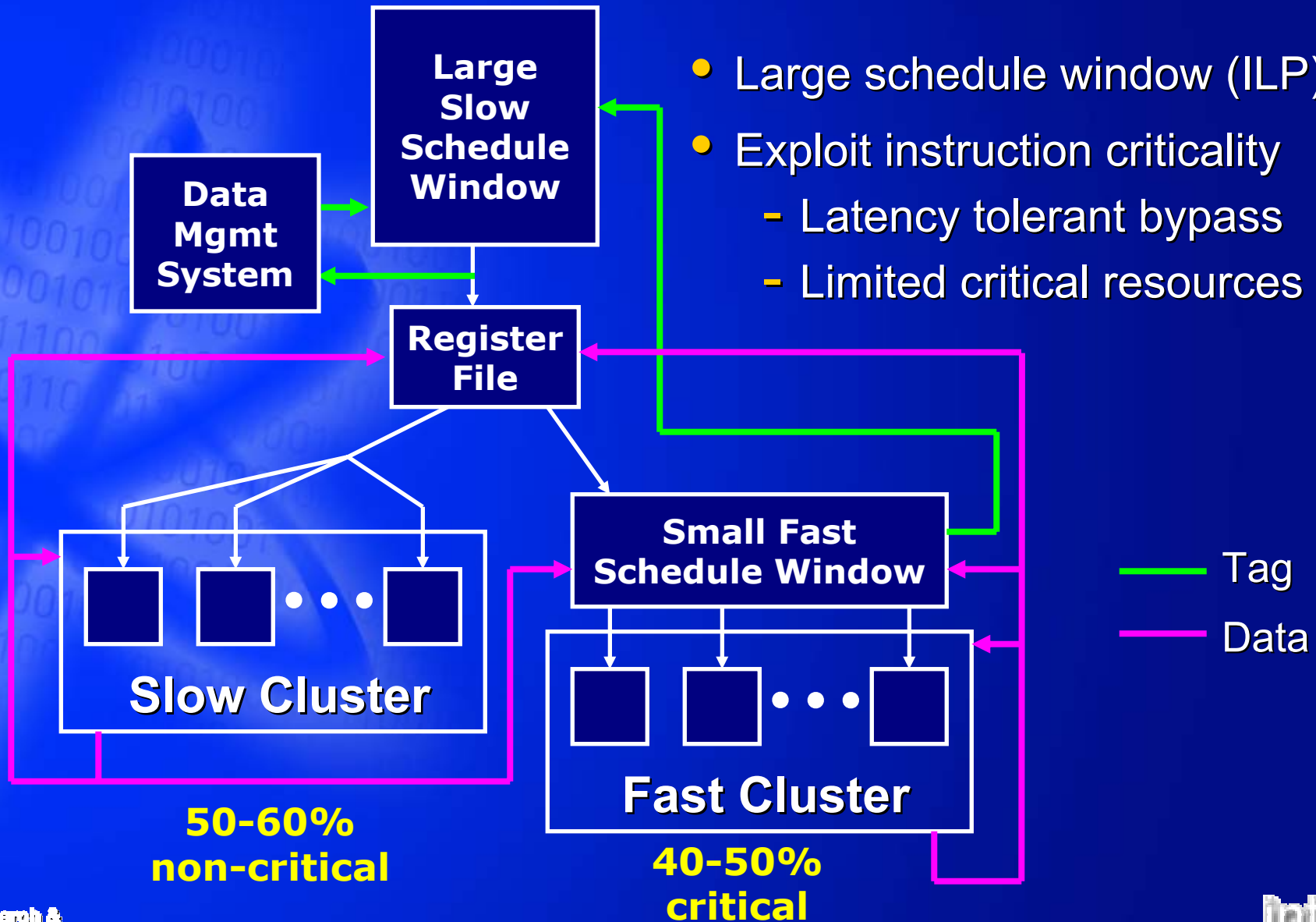


Throughput Oriented Design



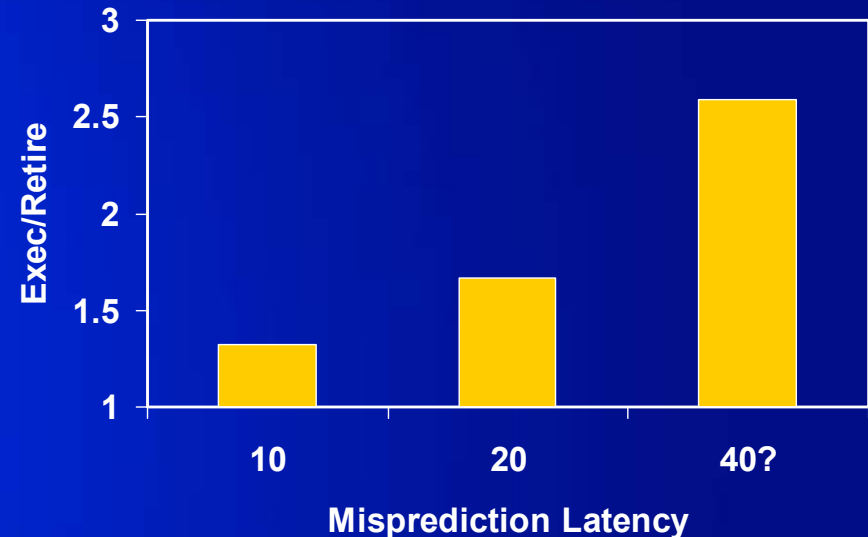
Critical Scheduling

- Large schedule window (ILP)
- Exploit instruction criticality
 - Latency tolerant bypass
 - Limited critical resources

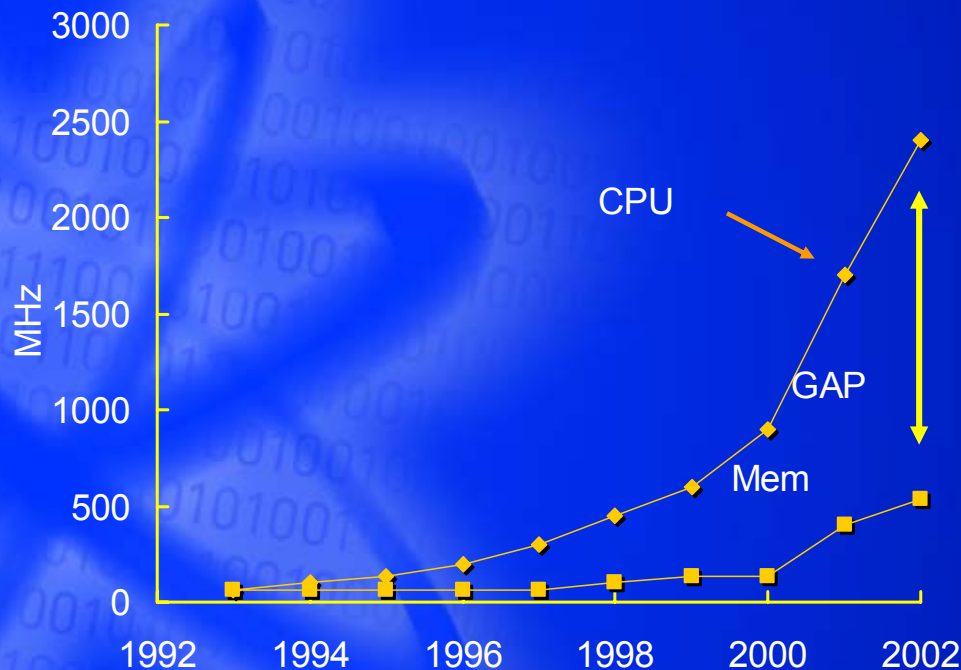


Recycling Waste

- Wasted execution
 - Spec Exec vs Retired
 - ~30% in 1st gen OOO
 - ~60% in 2nd gen OOO
 - ~160% in future
- Leverage info from wasted execution
- Improve branch Prediction
 - 30% reduction in misprediction rate
 - 18% to 48% less wasted execution
- Can we reuse the some of the execution result too?



Efficiency Through xMT



Thermals & power delivery
designed for full HW utilization

Single Thread

ST

Wait for Mem

Multi-thread

MT1

Wait for Mem

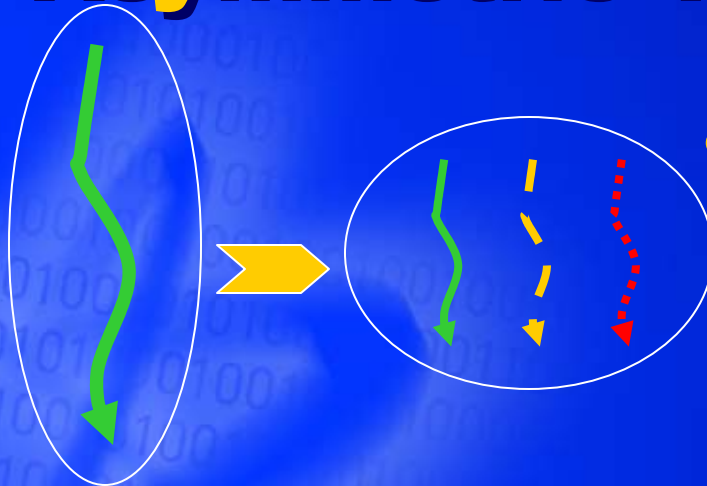
MT2

Wait

MT3

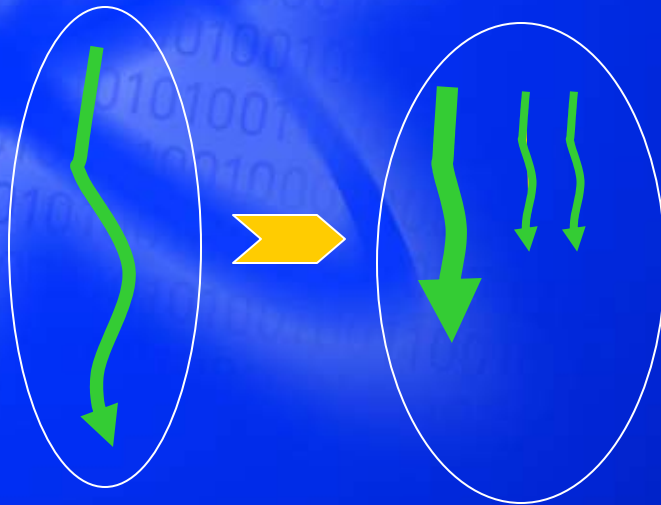
Multithreading improves performance
without impacting thermals & power delivery

Power Efficient Asymmetric Threads



- **Function Asymmetric Threading (w/co-processor ISA)**

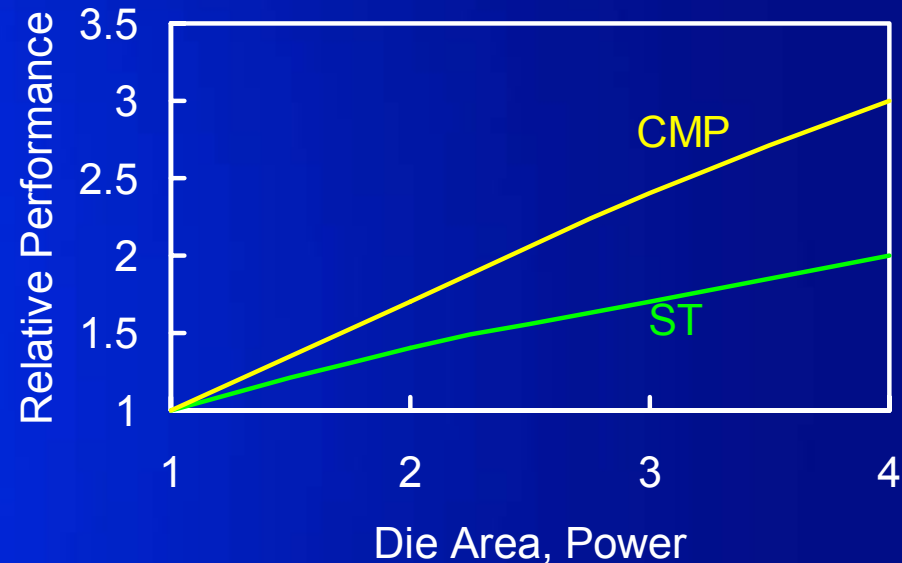
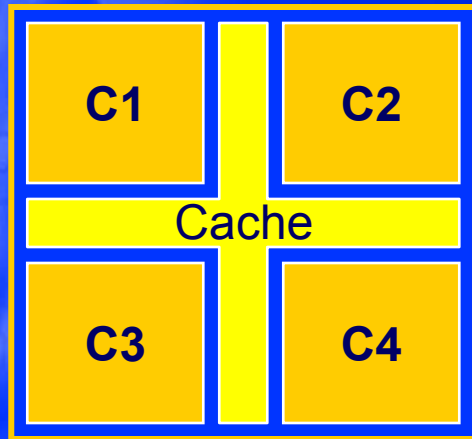
- Partition single thread into a main thread with special function threads
- Special function unit is more area and power efficient



- **Performance Asymmetric Threading (ISA compatible)**

- Serial code on heavy core
- Parallel code on smaller and power efficient core

Chip Multi-Processing



- Multi-core, each core MT
- Shared cache and front side bus
- Each core has different Vdd & Freq
- Core re-cycling to spread hot spots
- Lower junction temperature

Summary

- Technology scaling can and will continue
- Challenges to power and energy efficiency are real but surmountable..
- ..through evolutionary approaches to circuits and microarchitecture